## Search Notes



Appli	cation/Control No.	Applicant(s)/Patent Under Reexamination
10593	3424	RITTER ET AL.
Examiner		Art Unit
Hai Pl	han	2614

SEARCHED				
Class	Subclass	Date	Examiner	
381	381, 327, 110, 56, 57, 71.1, 92, 94.1	10/05/10	HP	

SEARCH NOTES				
Search Notes	Date	Examiner		
Inventor Search	10/05/10	HP		
EAST Search	10/05/10	HP		
Update Search	03/21/11	HP		
Update Search	09/24/11	HP		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
0.000				

/HAI PHAN/ Primary Examiner.Art Unit 2614

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